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Imaki et al. (43) **Pub. Date: Jun. 20, 2002**(54) **WAVELENGTH MONITOR AND
SEMICONDUCTOR LASER DEVICE**(30) **Foreign Application Priority Data**

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Takagi, Tokyo (JP)**Publication Classification**(51) **Int. Cl.⁷** H01S 3/13; H01S 3/00; H01S 5/00(52) **U.S. Cl.** 372/29.02; 372/43; 372/38.01**Correspondence Address:****Platon N. Mandros, Esq.****BURNS, DOANE, SWECKER & MATHIS,****L.L.P.****P.O. Box 1404****Alexandria, VA 22313-1404 (US)**(57) **ABSTRACT**

A wavelength monitor comprises a cylindrical lens configured to allow a laser beam emitted from a semiconductor laser to pass therethrough, first and second photodetectors configured to receive the laser beam through the cylindrical lens, and a wavelength filter disposed in an optical path between the semiconductor laser and the first photodetector.

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